UT54ACS365/UT54ACTS365

Hex Buffers/Line Drivers with Three-State Outputs

Datasheet November 2010 www.aeroflex.com/logic

FEATURES

- □ 1.2µ CMOS
 - Latchup immune
- □ High speed
- □ Low power consumption
- □ Single 5 volt supply
- □ Available QML Q or V processes
- □ Flexible package
 - 16-pin DIP
 - 16-lead flatpack
- UT54ACS365- SMD 5962-96586
- UT54ACTS365 SMD 5962-96587

DESCRIPTION

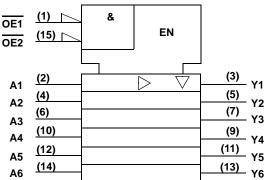
The UT54ACS365 and UT54ACTS365 are non-inverting hex buffer and line driver with three-state outputs. The output enables ($\overline{OE1}$ and $\overline{OE2}$) control the three-state outputs. If $\overline{OE1}$ or $\overline{OE2}$ is high, the outputs will be in a high impedance state. For data, both $\overline{OE1}$ and $\overline{OE2}$ must be low.

The devices are characterized over full military temperature range of -55° C to $+125^{\circ}$ C.

FUNCTION TABLE

INPUTS		OUTPUT	
OE1	OE2	А	Y
L	L	L	L
L	L	Н	Н
Х	Н	Х	Z
Н	Х	Х	Z

LOGIC SYMBOL

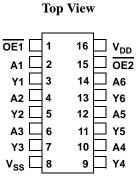




1. Logic symbol in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

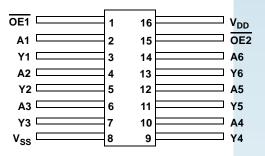


PINOUTS

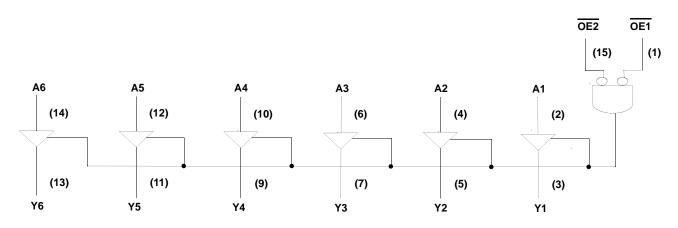


16-Pin DIP

16-Lead Flatpack Top View



LOGIC DIAGRAM



OPERATIONAL ENVIRONMENT¹

PARAMETER	LIMIT	UNITS
Total Dose	1.0E6	rads(Si)
SEU Threshold ²	80	MeV-cm ² /mg
SEL Threshold	120	MeV-cm ² /mg
Neutron Fluence	1.0E14	n/cm ²

Notes:

1. Logic will not latchup during radiation exposure within the limits defined in the table.

2. Device storage elements are immune to SEU affects.

ABSOLUTE MAXIMUM RATINGS

SYMBOL	PARAMETER	LIMIT	UNITS
V _{DD}	Supply voltage	-0.3 to 7.0	V
V _{I/O}	Voltage any pin	3 to V _{DD} +.3	V
T _{STG}	Storage Temperature range	-65 to +150	°C
T _J	Maximum junction temperature	+175	°C
T _{LS}	Lead temperature (soldering 5 seconds)	+300	°C
$\Theta_{\rm JC}$	Thermal resistance junction to case	20	°C/W
II	DC input current	±10	mA
P _D	Maximum power dissipation	1	W

Note:

1. Stresses outside the listed absolute maximum ratings may cause permanent damage to the device. This is a stress rating only, functional operation of the device at these or any other conditions beyond limits indicated in the operational sections is not recommended. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	LIMIT	UNITS
V _{DD}	Supply voltage	4.5 to 5.5	V
V _{IN}	Input voltage any pin	0 to V _{DD}	V
T _C	Temperature range	-55 to + 125	°C

DC ELECTRICAL CHARACTERISTICS 7

 $(V_{DD} = 5.0V \pm 10\%; V_{SS} = 0V^6, -55^{\circ}C < T_C < +125^{\circ}C);$ Unless otherwise noted, Tc is per the temperature range ordered.

SYMBOL	PARAMETER	CONDITION	MIN	MAX	UNIT
V _{IL}	Low-level input voltage ¹ ACTS ACS			0.8 .3V _{DD}	v
V _{IH}	High-level input voltage ¹ ACTS ACS		.5V _{DD} .7V _{DD}		v
I _{IN}	Input leakage current ACTS/ACS	$V_{IN} = V_{DD} \text{ or } V_{SS}$	-1	1	μΑ
V _{OL}	Low-level output voltage ³ ACTS ACS	$I_{OL} = 12.0 \text{mA}$ $I_{OL} = 100 \mu \text{A}$		0.40 0.25	v
V _{OH}	High-level output voltage ³ ACTS ACS	$I_{OH} = -12.0 \text{mA}$ $I_{OH} = -100 \mu \text{A}$.7V _{DD} V _{DD} - 0.25		v
I _{OZ}	Three-state output leakage current	$V_{O} = V_{DD}$ and V_{SS}	-30	30	μΑ
I _{OS}	Short-circuit output current ^{2,4} ACTS/ACS	$V_{O} = V_{DD}$ and V_{SS}	-300	300	mA
I _{OL}	Output current ¹⁰ (Sink)	$V_{IN} = V_{DD}$ or V_{SS} $V_{OL} = 0.4V$	12		mA
I _{OH}	Output current ¹⁰ (Source)	$V_{IN} = V_{DD}$ or V_{SS} $V_{OH} = V_{DD} - 0.4V$	-12		mA
P _{total}	Power dissipation ^{2, 8, 9}	$C_L = 50 pF$		1.8	mW/ MHz
I _{DDQ}	Quiescent Supply Current	V _{DD} = 5.5V		10	μΑ
ΔI _{DDQ}	Quiescent Supply Current Delta ACTS	For input under test $V_{IN} = V_{DD} - 2.1V$ For all other inputs $V_{IN} = V_{DD}$ or V_{SS} $V_{DD} = 5.5V$		1.6	mA
C _{IN}	Input capacitance ⁵	f = 1MHz @ 0V		15	pF
C _{OUT}	Output capacitance ⁵	f = 1MHz @ 0V		15	pF

Notes:

- 1. Functional tests are conducted in accordance with MIL-STD-883 with the following input test conditions: $V_{IH} = V_{IH}(min) + 20\%$, 0%; $V_{IL} = V_{IL}(max) + 0\%$, 50%, as specified herein, for TTL, CMOS, or Schmitt compatible inputs. Devices may be tested using any input voltage within the above specified range, but are guaranteed to $V_{IH}(min)$ and $V_{IL}(max)$.
- 2. Supplied as a design limit but not guaranteed or tested.
- 3. Per MIL-PRF-38535, for current density \leq 5.0E5 amps/cm², the maximum product of load capacitance (per output buffer) times frequency should not exceed 3,765 pF/MHz.
- 4. Not more than one output may be shorted at a time for maximum duration of one second.
- 5. Capacitance measured for initial qualification and when design changes may affect the value. Capacitance is measured between the designated terminal and V_{SS} at frequency of 1MHz and a signal amplitude of 50mV rms maximum.
- 6. Maximum allowable relative shift equals 50mV.
- 7. All specifications valid for radiation dose \leq 1E6 rads(Si).
- 8. Power does not include power contribution of any TTL output sink current.
- 9. Power dissipation specified per switching output.
- 10. This value is guaranteed based on characterization data, but not tested.

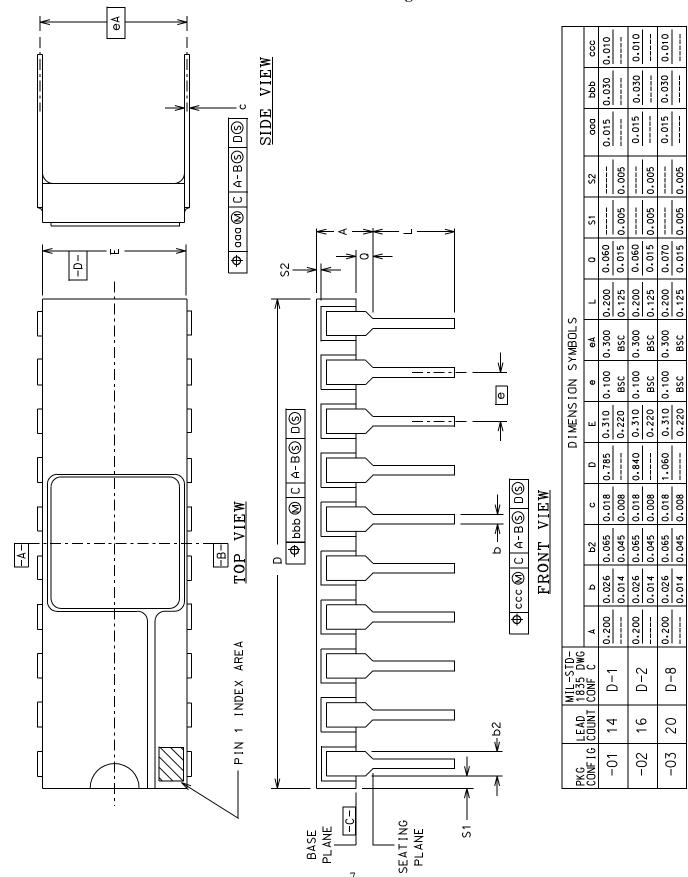
AC ELECTRICAL CHARACTERISTICS ² ($V_{DD} = 5.0V \pm 10\%$; $V_{SS} = 0V^{-1}$, -55°C < T_C < +125°C); Unless otherwise noted, Tc is per the temperature range ordered.

SYMBOL	PARAMETER	MINIMUM	MAXIMUM	UNIT
t _{PLH}	Data to output	2	11	ns
t _{PHL}	Data to output	2	13	ns
t _{PZL}	\overline{OE} low to output active	2	14	ns
t _{PZH}	OE low to output active	2	15	ns
t _{PLZ}	OE high to output three-state	2	12	ns
t _{PHZ}	OE high to output three-state	2	14	ns

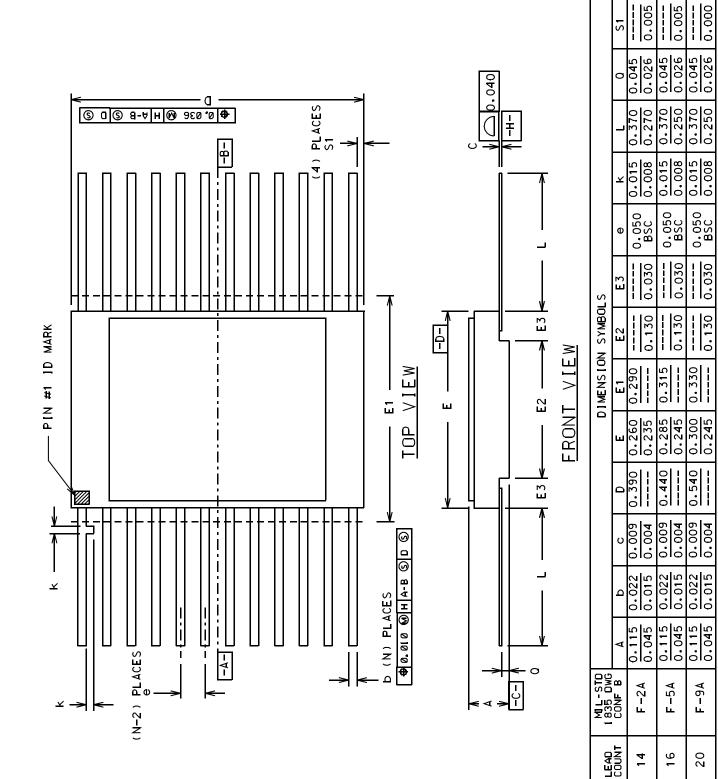
Notes:
1. Maximum allowable relative shift equals 50mV.
2. All specifications valid for radiation dose ≤ 1E6 rads(Si).

PACKAGING

Side-Brazed Packages



FLATPACK PACKAGES



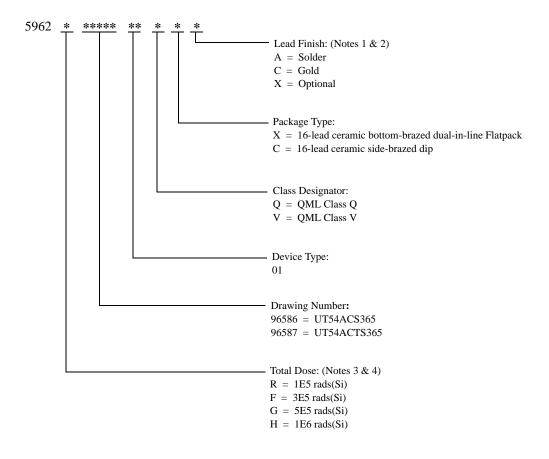
PKG CONFI G

-03

-05

-04

UT54ACS365/UT54ACTS365: SMD



Notes:

- 1. Lead finish (A,C, or X) must be specified.
- 2. If an "X" is specified when ordering, part marking will match the lead finish and will be either "A" (solder) or "C" (gold).
- 3. Total dose radiation must be specified when ordering. QML Q and QML V not available without radiation hardening. For prototype inquiries, contact factory.
- 4. Device type 02 is only offered with a TID tolerance guarantee of 3E5 rads(Si) or 1E6 rads(Si) and is tested in accordance with MIL-STD-883 Test Method 1019 Condition A and section 3.11.2. Device type 03 is only offered with a TID tolerance guarantee of 1E5 rads(Si), 3E5 rads(Si), and 5E5 rads(Si), and is tested in accordance with MIL-STD-883 Test Method 1019 Condition A.

Aeroflex Colorado Springs - Datasheet Definition

Advanced Datasheet - Product In Development Preliminary Datasheet - Shipping Prototype Datasheet - Shipping QML & Reduced Hi-Rel

COLORADO Toll Free: 800-645-8862 Fax: 719-594-8468 **INTERNATIONAL** Tel: 805-778-9229 Fax: 805-778-1980

SE AND MID-ATLANTIC Tel: 321-951-4164 Fax: 321-951-4254 **WEST COAST** Tel: 949-362-2260 Fax: 949-362-2266 Fax: 603-888-4585 CENTRAL Tel: 719-594-8017

Fax: 719-594-8468

Tel: 603-888-3975

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www.aeroflex.com info-ams@aeroflex.com

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